INTERNATIONAL SEARCH REPORT. 2007

10/5/1005 Application No 03/06299

A. CLASSIFI	CATION OF SUBJECT MATTER G01B21/20 G01B11/24 G06T17/20	G06T7/60	
140 /	QUIDZ1/20 QUIDI1/24 QUID.1/10		·
According to	: International Patent Classification (IPC) or to both national classification	and IPC	
B. FIELDS S	EARCHED		
Minimum doc IPC 7	sumentation searched (classification system followed by classification s $601B$ $606T$	symbols)	
Documentation	on searched other than minimum documentation to the extent that such	documents are included in the fields sea	arched
Electronic da	ata base consulted during the international search (name of data base	and, where practical, search terms used)	
	ternal, WPI Data, INSPEC		
C. DOCUME	ENTS CONSIDERED TO BE RELEVANT		
Category °	Citation of document, with indication, where appropriate, of the relevant	ant passages	Relevant to claim No.
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χFu	rther documents are listed in the continuation of box C.	X Patent family members are listed	in annex.
A docur cons *E* earlie filing *L* docur which citat *O* docu othe *P* docur later	ment defining the general state of the art which is not sidered to be of particular relevance or document but published on or after the international grant which may throw doubts on priority daim(s) or	"T" later document published after the in or priority date and not in conflict wind cited to understand the principle or invention "X" document of particular relevance; the cannot be considered novel or canninvolve an inventive step when the cannot be considered to involve an document of particular relevance; the cannot be considered to involve an document is combined with one or ments, such combination being obvin the art. "&" document member of the same pate Date of mailing of the international s	in the application but theory underlying the claimed invention not be considered to document is taken alone e claimed invention inventive step when the more other such document inventions to a person skilled
Name an	d mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl,	Authorized officer Santos, M	

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